

**A/D Converter Series** 

# Successive Approximation A/D Converter 12 bit, 0.5 MSPS to 1 MSPS, 2.7 V to 5.25 V, 1-channel, SPI Interface

## BU79100G-LA

#### **General Description**

This is the product guarantees long time support in industrial market.

The BU79100G-LA is a general purpose, 12 bit 1-channel successive approximation AD converter. The sampling rate of BU79100G-LA ranges from 0.5 MSPS to 1 MSPS.

#### Features

- Long Time Support Product for Industrial Applications
- Maximum 1 MSPS Sampling Rate
- Low Power Consumption
- Small SSOP6 Package Compatible with SOT23-6
  Serial Interface Compatible with
- SPI/QSPI/MICROWIRE
- Operational Supply Voltage Range: 2.7 V to 5.25 V
- Single-ended Input
- Output Code in Straight Binary Format

#### Applications

- Industrial Equipment
- Instrumentation and Control Systems
- Motor Control Systems
- Data Acquisition Systems

#### Key Specifications

Supply Voltage Range:	2.70 V to 5.25 V
Sampling Rate:	0.5 MSPS to 1.0 MSPS
Power Consumption:	
(In 1MSPS Operation)	8 mW @V <sub>A</sub> = 5 V (Typ)
	$1.5 \text{ mW} @V_{A} = 3 \text{ V} (Typ)$
INL:	-1.1 LSB to +1.0 LSB
DNL:	-1.0 LSB to +1.0 LSB
SNR:	71.5 dB @ $V_A = 3 V$ (Tvp)

- SINAD:  $71.0 \text{ dB} @. V_A = 3 \text{ V} (Typ)$
- Operating Temperature Range: -40 °C to +85 °C

## Package

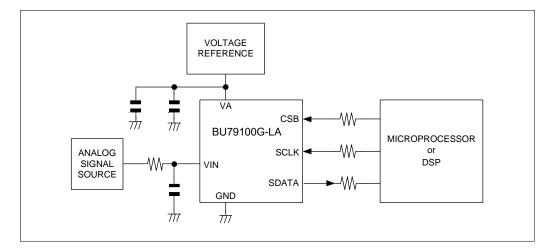
SSOP6

## W (Typ) x D (Typ) x H (Max)

2.9 mm x 2.8 mm x 1.25 mm



## Typical Application Circuit

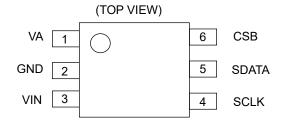


OProduct structure : Silicon integrated circuit OThis product has no designed protection against radioactive rays.

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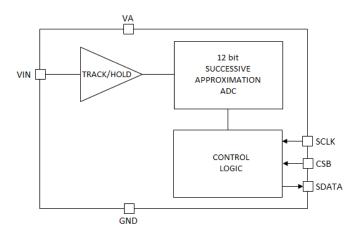
## **Pin Configuration**



## **Pin Descriptions**

Pin No.	Pin Name	Function			
1	VA	Power supply pin. This voltage is the full scale of the analog input.			
2	GND	Ground pin. This voltage level is the zero scale of the analog input.			
3	VIN	Analog input pin. The voltage range must be between 0 V and V <sub>A</sub> .			
4	SCLK	Digital clock input pin.			
5	SDATA	Digital data output pin.			
6	CSB	Chip select pin. A/D conversion starts at the falling edge of this signal.			

## **Block Diagram**



## Absolute Maximum Ratings (Ta = 25 °C)

Parameter	Symbol	Rating	Unit
Supply Voltage	VA	5.7	V
Analog Input Voltage	V <sub>IN</sub>	-0.3 to V <sub>A</sub> +0.3	V
Digital Input Voltage	Vdin	-0.3 to +5.7	V
Maximum Junction Temperature	Tjmax	125	°C
Storage Temperature Range	Tstg	-55 to +125	°C

Caution 1: Operating the IC over the absolute maximum ratings may damage the IC. The damage can either be a short circuit between pins or an open circuit

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#### Thermal Resistance (Note 1)

Decemptor	Symbol	Thermal Res	Linit				
Parameter	Symbol	1s <sup>(Note 3)</sup>	2s2p <sup>(Note 4)</sup>	Unit			
SSOP6							
Junction to Ambient	θ <sub>JA</sub>	376.5	185.4	°C/W			
Junction to Top Characterization Parameter <sup>(Note 2)</sup>	$\Psi_{JT}$	40	30	°C/W			

(Note 1) Based on JESD51-2A (Still-Air).

(Note 1) based on SEOD 122 (GuirAn).
 (Note 2) The thermal characterization parameter to report the difference between junction temperature and the temperature at the top center of the outside surface of the component package.
 (Note 3) Using a PCB board based on JESD51-3.
 (Note 4) Using a PCB board based on JESD51-7.

Note 4) Using a PCB board based of	JII JE3D31-7.			
Layer Number of Measurement Board	Material	Board Size		
Single	FR-4	114.3 mm x 76.2 mm x	c 1.57 mmt	
Тор				
Copper Pattern	Thickness			
Footprints and Traces	70 µm			
Layer Number of Measurement Board	Material	Board Size		
4 Layers	FR-4	114.3 mm x 76.2 mm x 1.6 mmt		
Тор		2 Internal Layers		Bottom
Copper Pattern	Thickness	Copper Pattern	Thickness	Copper Pattern
Footprints and Traces	70 µm	74.2 mm x 74.2 mm	35 µm	74.2 mm x 74.2 mm

Thickness 70 µm

## **Recommended Operating Conditions**

Parameter	Symbol	Min	Тур	Max	Unit
Supply Voltage	VA	2.70	-	5.25	V
Analog Input Voltage	Vin	0	-	VA	V
Digital Input Voltage	Vdin	0	-	5.25	V
Operating Temperature	Topr	-40	+25	+85	°C
Clock Frequency	fsclk	10	-	20	MHz
Sampling Rate	f <sub>S</sub>	0.5	-	1.0	MSPS

## **Electrical Characteristics**

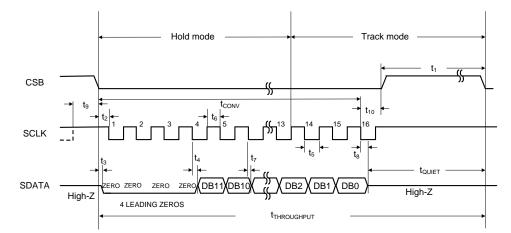
Unless otherwise specified, Ta = -40 °C to +85 °C (typical: Ta = 25 °C), V<sub>A</sub> = 2.7 V to 5.25 V, f<sub>SCLK</sub> = 20 MHz, f<sub>S</sub> = 1 MSPS

Parameter	Symbol	Min	Тур	Max	Unit	Conditions
Statistic Converter Characteristics			-			
Resolution with No missing codes	Res	-	12	-	bit	V <sub>A</sub> = 2.7 V to 3.6 V
Integral Non-linearity	I <sub>NL</sub>	-1.1	-	+1.0	LSB	V <sub>A</sub> = 2.7 V to 3.6 V, 25 °C
Differential Non-linearity	D <sub>NL</sub>	-1.0	-	+1.0	LSB	V <sub>A</sub> = 2.7 V to 3.6 V, 25 °C
Offset Error	OE	-1.2	±0.2	+1.2	LSB	V <sub>A</sub> = 2.7 V to 3.6 V, 25 °C
Gain Error	GE	-1.2	±0.3	+1.2	LSB	V <sub>A</sub> = 2.7 V to 3.6 V, 25 °C
Dynamic Converter Characteristics (fin	i = 100 kHz,				<u> </u>	
Signal to Noise and Distortion Ratio1	SINAD1	70	71	-	dB	V <sub>A</sub> = 2.7 V to 3.6 V, 25 °C
Signal to Noise and Distortion Ratio2	SINAD2	68	70	-	dB	V <sub>A</sub> = 4.75 V to 5.25 V, 25 °C
Signal to Noise Ratio1	S <sub>NR1</sub>	70.8	71.5	-	dB	V <sub>A</sub> = 2.7 V to 3.6 V, 25 °C
Signal to Noise Ratio2	S <sub>NR2</sub>	68.8	71.0	-	dB	V <sub>A</sub> = 4.75 V to 5.25 V, 25 °C
Total Harmonic Distortion	T <sub>HD</sub>	-	-80	-	dB	V <sub>A</sub> = 2.7 V to 3.6 V
Spurious-free Dynamic Range	SFDR	-	82	-	dB	V <sub>A</sub> = 2.7 V to 3.6 V
Effective Number of Bits1	ENOB1	11.3	11.5	-	bit	V <sub>A</sub> = 2.7 V to 3.6 V, 25 °C
Effective Number of Bits2	ENOB2	11.0	11.3	-	bit	V <sub>A</sub> = 4.75 V to 5.25 V, 25 °C
Inter-modulation Distortion1 (Second Order Term)	I <sub>MD1</sub>	-	-78	-	dB	V <sub>A</sub> = 5.25 V, 103.5 kHz, 113.5 kHz
Inter-modulation Distortion2 (Third Order term)	I <sub>MD2</sub>	-	-76	-	dB	V <sub>A</sub> = 5.25 V, 103.5 kHz, 113.5 kHz
Full Power Band Width1	f <sub>PBW1</sub>	-	10.1	-	MHz	$V_{\rm A} = 5 V$
Full Power Band Width2	fPBW2	-	7.2	-	MHz	$V_A = 3 V$
Aperture Delay	t <sub>AD</sub>	-	4.3	-	ns	V <sub>A</sub> = 5 V
Aperture Jitter	t <sub>AJ</sub>	-	30	-	ps	V <sub>A</sub> = 5 V
Clock Frequency	fsclk	10	-	20	MHz	
Sampling Rate	fs	500 k	-	1 M	SPS	
Track/Hold Acquisition Time	tACQ	-	-	350	ns	
Analog Input Characteristics		1	1		1	<u> </u>
Input Voltage Range	VIN	0	-	VA	V	
Input DC Leakage Current	ILEAK	-1.0	±0.1	+1.0	μA	V <sub>IN</sub> = 0 V or V <sub>A</sub>
Input Capacitance1	C <sub>INA1</sub>	-	28	-	pF	track mode, V <sub>A</sub> = 5 V
Input Capacitance2	CINA2	-	4	-	pF	hold mode, $V_A = 5 V$
Digital Input Characteristics		1	<u> </u>		L .	<u> </u>
High Input Voltage1	VIH1	2.4	-	-	V	V <sub>A</sub> = 5.25 V
High Input Voltage2	V <sub>IH2</sub>	2.1	-	-	V	V <sub>A</sub> = 3.6 V
Low Input Voltage1	VIL1	-	-	0.8	V	$V_A = 5 V$
Low Input Voltage2	VIL2	-	-	0.4	V	$V_A = 3 V$
Input Current	I <sub>IND</sub>	-1.0	±0.1	+1.0	μA	$V_{IND} = 0 V \text{ or } V_A$
Input Capacitance	CIND	-	2.5	-	pF	
Digital Output Characteristics		1			<u> </u>	1
Output High Voltage1	V <sub>OH1</sub>	V <sub>A</sub> -0.20	VA-0.03	-	V	Isource = 200 µA
Output High Voltage2	V <sub>OH2</sub>	-	V <sub>A</sub> -0.1	-	V	ISOURCE = 1 mA
Output Low Voltage1	Vol.1	-	0.02	0.40	V	Isink = 200 μA
Output Low Voltage2	V <sub>OL2</sub>	-	0.1	-	V	Isink = 1 mA
High-Z Leakage Current	loz	-10.0	±0.1	+10.0	μA	$V_{OZ} = 0 V \text{ or } V_A$
High-Z Output Capacitance	Соцт	-	2	-	pF	
Current Consumption		1	_		<u> </u>	1
Operational Current Consumption1	I <sub>A1</sub>	-	1.6	2.8	mA	V <sub>A</sub> = 5.25 V, f <sub>S</sub> = 1 MSPS
Operational Current Consumption2	IA1		0.5	1.2	+	$V_A = 3.6 V, f_S = 1 MSPS$

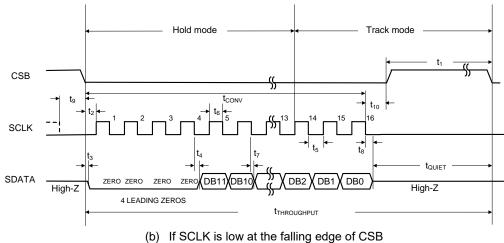
## **Timing Specifications**

Unless otherwise specified, Ta = -40 °C to +85 °C (Typical: Ta = 25 °C), VA = 2.7 V to 5.25 V, f<sub>SCLK</sub> = 10 M to 20 MHz, CL = 25 pF

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Parameter	Symbol	Min	Тур	Max	Unit	Conditions
Conversion Time	t <sub>CONV</sub>	-	16	-	SCLK	
CSB Pulse Width	t1	10	-	-	ns	
CSB Setup Time	t2	10	-	-	ns	
SDATA Enable Time	t3	-	-	20	ns	
SDATA Access Time1	t4	-	-	40	ns	V <sub>A</sub> = 2.7 V to 3.6 V
SDATA Access Time2	t4	-	-	20	ns	V <sub>A</sub> = 4.75 V to 5.25 V
SCLK Low Pulse Width	t5	0.4xt <sub>SCLK</sub>	-	-	ns	
SCLK High Pulse Width	t <sub>6</sub>	0.4xt <sub>SCLK</sub>	-	-	ns	
SDATA Hold Time1	t7	7	-	-	ns	V <sub>A</sub> = 2.7 V to 3.6 V
SDATA Hold Time2	t7	5	-	-	ns	V <sub>A</sub> = 4.75 V to 5.25 V
SDATA Disable Time1	t <sub>8</sub>	6	-	25	ns	V <sub>A</sub> = 2.7 V to 3.6 V
SDATA Disable Time2	t <sub>8</sub>	5	-	25	ns	V <sub>A</sub> = 4.75 V to 5.25 V
CSB Hold Time	t9	10	-	-	ns	
SCLK Setup Time	t10	10	-	-	ns	
Quiet Time	tquiet	50	-	-	ns	
Power-Up Time	tpowup	-	1	-	μs	
Throughput Period	t <sub>THROUGHPUT</sub>	1	-	20	μs	



## (a) If SCLK is high at the falling edge of CSB





(Note 5) When the BU79100G-LA is used at the sampling frequency of 1 MSPS, it is recommended to hold SCLK high at the falling edge of CSB as shown in Figure 1(a). (See also "3. Serial Interface" on page 13.)

## **Term Definitions**

#### ACQUISITION TIME:

At the 13<sup>th</sup> rising edge of SCLK, the mode is changed from Hold mode to Track mode and the sampling capacitor starts to be charged. It is the time when the voltage of the sampling capacitor equals input voltage from the charge start.

#### APERTURE DELAY:

It is defined as the time when the input voltage is held since a sampling capacitor was separated with outside by a falling edge of CSB.

#### APERTURE JITTER:

The variation in the aperture delays in sampling operations. Aperture jitter gets to affect output noise.

#### INTEGRAL NON-LINEARLITY (INL):

It is a measure of the deviation of each individual code from a line drawn from zero scale (0.5 LSB below the first code transition) through full scale (0.5 LSB above the last code transition). The deviation of any given code from this straight line is measured from the center of that code value.

#### DIFFERENTIAL NON-LINEARLITY (DNL):

It is the measure of the maximum deviation from the ideal step size of 1 LSB.

## OFFSET ERROR (OE):

It is the deviation of the first code transition "(000...000) to (000...001)" from the ideal of 0.5 LSB.

#### FULL SCALE ERROR (FSE):

It is the deviation of the last code transition "(111...110) to (111...111)" from the ideal of "VA-1.5 LSB".

#### GAIN ERROR (GE):

It is defined as full scale error minus offset error.

#### TOTAL HARMONIC DISTORTION (THD):

It is the ratio, expressed in dB or dBc, of the RMS total of the first five harmonic components at the output to the RMS level of the input signal frequency as seen at the output. THD is calculated as

THD = 20 · log<sub>10</sub> 
$$\sqrt{\frac{A_{f2}^2 + \dots + A_{f6}^2}{A_{f1}^2}}$$

where  $A_{f1}$  is the RMS power of the input frequency at the output and  $A_{f2}$  through  $A_{f6}$  are the RMS power in the first 5 harmonic frequencies.

#### SIGNAL TO NOISE AND DISTORTION RATIO (SINAD):

It is the ratio, expressed in dB, of the RMS value of the input signal to the RMS value of all other spectral components below half the sampling frequency, including harmonics but excluding DC component.

## EFFECTIVE NUMBER OF BITS (ENOB):

It is another method of specifying Signal to Noise and Distortion Ratio. ENOB is defined as "(SINAD-1.76) / 6.02" and says that the converter is equivalent to a perfect A/D converter of this number of bits.

#### SIGNAL TO NOISE RATIO (SNR):

It is the ratio, expressed in dB, of the RMS value of the input signal to the RMS value of all other spectral components below half the sampling frequency, not including harmonics and DC component.

## SPURIOUS FREE DYNAMIC RANGE (SFDR):

It is the difference, expressed in dB, between the RMS value of the input signal to the RMS value of the peak spurious spectral component, where a peak spurious spectral component is any spurious signal present in the output spectrum that is not present at the input.

#### CONVERSION TIME:

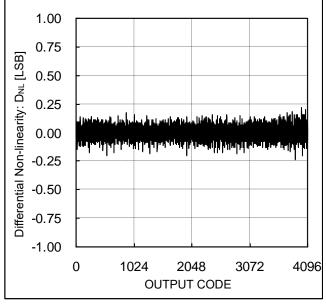
It is the required time for the A/D converter to convert the input signal to the digital code.

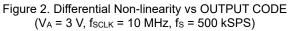
#### THROUGHPUT PERIOD:

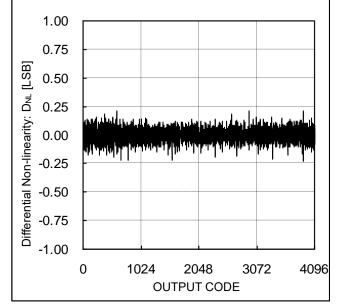
It is the period that should be used as an interval time between any adjacent conversions.

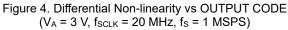
## **Typical Performance Curves**

(Reference Data) Unless otherwise noted, Ta = 25 °C.









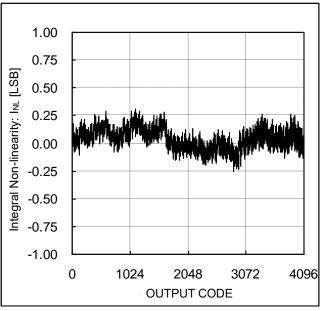


Figure 3. Integral Non-linearity vs OUTPUT CODE (V<sub>A</sub> = 3 V,  $f_{SCLK}$  = 10 MHz,  $f_{S}$  = 500 kSPS)

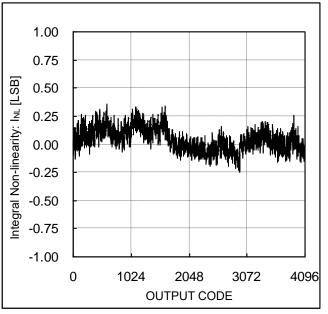


Figure 5. Integral Non-linearity vs OUTPUT CODE (VA = 3 V,  $f_{SCLK}$  = 20 MHz,  $f_{S}$  = 1 MSPS)

## **Typical Performance Curves – continued**

(Reference Data)

Unless otherwise noted, Ta = 25 °C, f<sub>IN</sub> = 100 kHz.

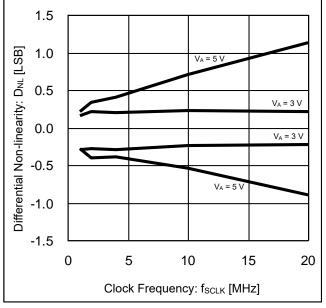


Figure 6. Differential Non-linearity vs Clock Frequency

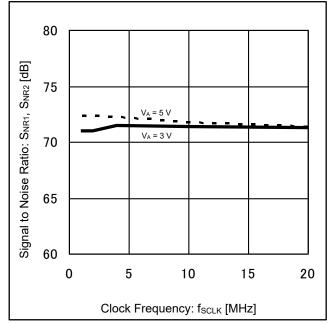


Figure 8. Signal to Noise Ratio vs Clock Frequency

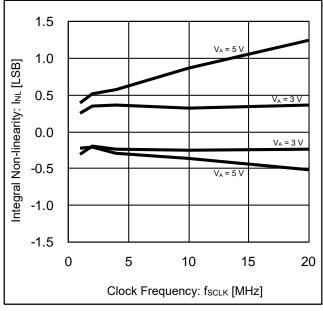


Figure 7. Integral Non-linearity vs Clock Frequency

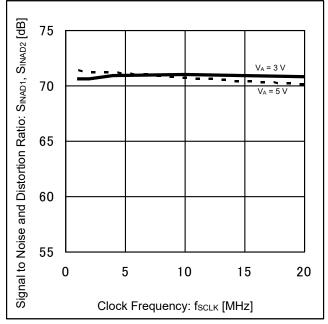


Figure 9. Signal to Noise and Distortion Ratio vs Clock Frequency

## **Typical Performance Curves – continued**

(Reference Data)

Unless otherwise noted, Ta = 25 °C, f<sub>IN</sub> = 100 kHz.

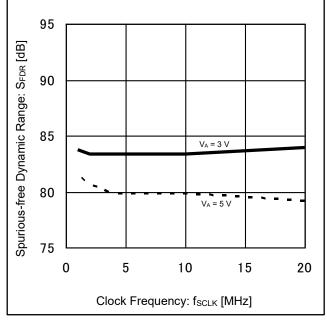
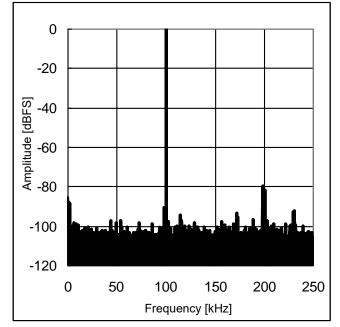
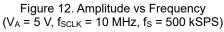


Figure 10. Spurious-free Dynamic Range vs Clock Frequency





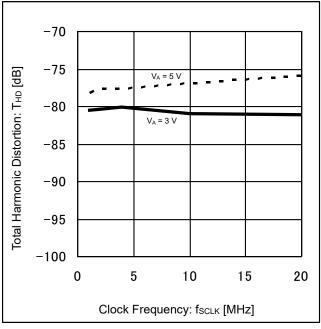


Figure 11. Total Harmonic Distortion vs Clock Frequency

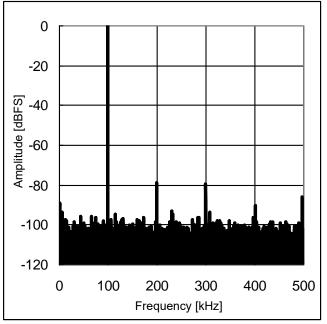


Figure 13. Amplitude vs Frequency  $(V_A = 5 V, f_{SCLK} = 20 \text{ MHz}, f_S = 1 \text{ MSPS})$ 

## **Description of Functions**

1. Overview of A/D Conversion Process

BU79100G-LA is a successive-approximation A/D converter designed with a charge-redistribution D/A converter. Simplified schematics of the A/D converter are shown in Figure 14 and Figure 15.

Figure 14 shows the A/D converter in Track mode: the switch SW1 is in the position A, SW2 is closed and balances the comparator. Then, the sampling capacitor is charged with the analog input voltage  $V_{IN}$ .

Figure 15 shows the A/D converter in Hold mode. When a conversion starts, the A/D converter goes into Hold mode: SW2 becomes open, SW1 connects the sampling capacitor to ground through the pin B and the comparator loses its balance. The control logic controls the input voltage of the comparator via the sampling capacitors of the charge-redistribution D/A converter to get the comparator back into a balanced state. A/D conversion finishes when the comparator balances again. The control logic also generates the output code of the A/D converter.

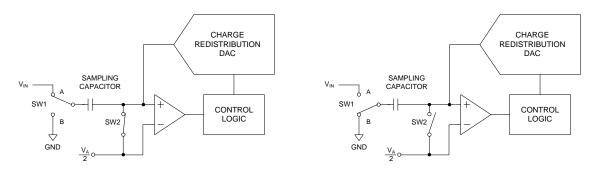


Figure 14. Track mode

Figure 15. Hold mode

2. Ideal Transfer Characteristics

Figure 16 shows the ideal transfer characteristics of BU79100G-LA. Code transitions occur midway between successive integer LSB values, such as 0.5 LSB, 1.5 LSB, and so on. The LSB size for the BU79100G-LA is V<sub>A</sub> / 4096. The output code format of the A/D converter is straight binary.

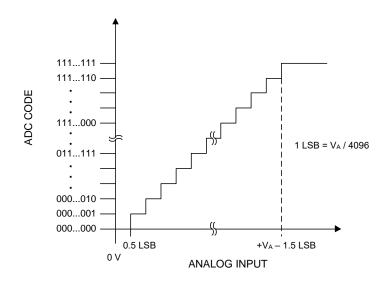


Figure 16. Ideal Transfer Characteristics

## **Description of Functions – continued**

## 3. Serial Interface

The serial interface timing is shown in Figure 17. When CSB goes low, both a conversion process and data transfer are started. At the falling edge of CSB, SDATA changes its state from High-Z to Low, the converter moves from Track mode to Hold mode. A tracked input signal is sampled and held for conversion at this point. The converter returns from Hold mode back to Track mode at the rising edge of SCLK subsequent to the 13<sup>th</sup> falling edge of it. SDATA goes back to High-Z at the 16<sup>th</sup> falling edge of SCLK or at the rising edge of CSB. After a conversion, the quiet time t<sub>QUIET</sub> must be satisfied before the next conversion triggered by the falling edge of CSB.

Sixteen SCLK cycles are needed to read a complete data of the A/D conversion from BU79100G-LA. First, four leading zeros come out from SDATA. Then, the 12 bit data comes out bit by bit, starting from the MSB. The first zero is clocked out at the falling edge of CSB. The remaining leading 3 zeros and data bits are clocked out to SDATA at the falling edge of SCLK; the host IC, the receiver of the A/D conversion data, is intended to receive the data at the subsequent falling edge of SCLK.

To perform A/D conversion properly, the BU79100G-LA needs at least 16 SCLK cycles while CSB is low. If an A/D conversion is interrupted in the middle of the conversion with CSB going to high before the 16<sup>th</sup> SCLK falling edge, the following A/D conversion may not be performed normally. Therefore, it is necessary that equal to or more than 16 falling edges of SCLK exist while CSB is low.

In addition, SCLK should be held either high or low at the falling edge of CSB. If SCLK is low at the falling edge of CSB, as shown in Figure 17(b), a Hold mode time length is about a half clock period longer than one if SCLK is high as shown in Figure 17(a). Therefore, when the BU79100G-LA is used at the sampling frequency of 1 MSPS, it is recommended to hold SCLK high at the falling edge of CSB, as shown in Figure 17(a), in order to ensure sufficient Track mode time for the maximum acquisition time.

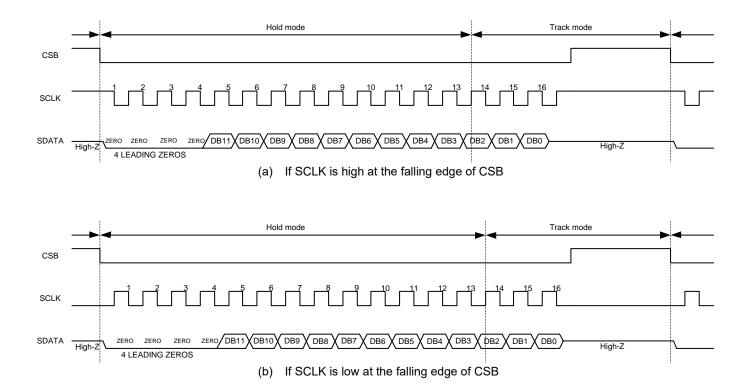


Figure 17. Serial Interface Timing

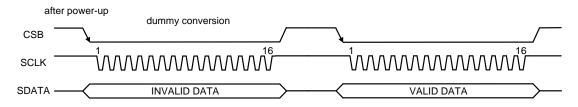
## **Description of Functions – continued**

4. Dummy Conversion

Dummy conversions are necessary in the following cases.

(1) A/D conversion after power-up

The first A/D conversion data after applying power to the BU79100G-LA is invalid. Therefore, a dummy conversion is necessary after power-up. In addition, the power-up time is satisfied with a cycle of the dummy conversion.





(2) A/D conversion after a stop period more than the maximum throughput time

The BU79100G-LA may stop performing A/D conversion between some A/D conversion cycles. If the maximum limit of the throughput period of 20 µs is violated, the first A/D conversion data after the resumption is not valid similar to the case after power-up. Therefore, a dummy conversion cycle is necessary.

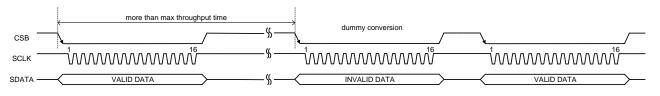


Figure 19. A/D conversion after a long suspension

## **Application Example**

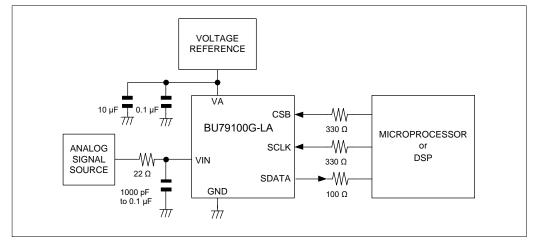


Figure 20. Application Circuit

As shown in Figure 20, a power supply pin connects voltage source and put two bypass capacitors for the high frequency and low frequency noise between VA and GND to make the maximum use of the A/D converter's capability. Ceramic capacitors of 0.1  $\mu$ F and 1  $\mu$ F to 10  $\mu$ F are to be used as bypass capacitor for BU79100G-LA. Especially, the capacitor of 0.1  $\mu$ F should be placed as close to the VA pin of BU79100G-LA as possible.

Because the voltages of VA and GND are used as the reference voltages for the A/D converter, the deviation of the supply voltage directly affects the full scale and has much influence on its characteristics. Therefore, the fully stable supply voltage should be connected to VA.

The output impedance of the analog input signal source should be small enough. Charge in the sampling capacitor is swept out to the VIN pin at the transition from Hold mode to Track mode because of the difference of the voltage between the input signal voltage and the sampling capacitor voltage. This charge could cause undesirable voltage deviation. If influence of the deviation remains at the transition from Track mode to Hold mode, it could cause the conversion error.

If a buffer amplifier is used to get low output impedance, high-speed response is required of the buffer amplifier. A decoupling capacitor and a resister on the VIN analog input could support the amplifier to reduce the influence of the charge.

The voltage fluctuation on the supply and ground pins is caused by the charge and discharge of the digital input and output pins through the digital signals. This fluctuation can be reduced by inserting resisters serially to the digital input and output pins. The resistance values must be small enough not to cause critical delay errors. It is more effective to place these resisters as close to the digital pins as possible.

## I/O Equivalence Circuit

(1) Analog Input Pin

The equivalent analog input circuit is shown in Figure 21. The diodes,  $D_1$  and  $D_2$ , are placed for ESD protection. If the analog input voltage is more than "V<sub>A</sub>+0.3 V", or less than "GND–0.3 V", these diodes are turned on and forward current is generated. This current might cause malfunction or irreversible damage to BU79100G-LA. The capacitance value of the C<sub>1</sub> in Figure 21 is typically 4 pF, derived from the package parasitic capacitance. The R<sub>1</sub> is the resistance of the track/hold switch, typically 500  $\Omega$ . The C<sub>2</sub> is the sampling capacitance of BU79100G-LA, and the capacitance value is typically 24 pF.

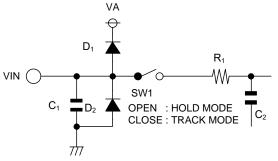


Figure 21. Analog Input Equivalent Circuit

(2) Digital Input and Output Pins

The equivalent digital input circuit is shown in Figure 22. Digital input pins, CSB and SCLK, don't have any diodes to VA. Thus, the maximum rating of " $V_A$ +0.3 V" is not applied to these digital input pins. Digital input voltage range is 5.25 V in ground reference regardless of the supply voltage  $V_A$ . This enables BU79100G-LA to be interfaced with a wide range of logic levels, independent of the supply voltage.

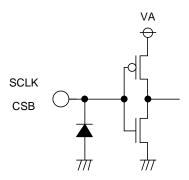


Figure 22. Equivalent Digital Input Circuit

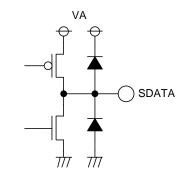


Figure 23. Equivalent Digital Output Circuit

## **Operational Notes**

## 1. Reverse Connection of Power Supply

Connecting the power supply in reverse polarity can damage the IC. Take precautions against reverse polarity when connecting the power supply, such as mounting an external diode between the power supply and the IC's power supply pins.

## 2. Power Supply Lines

Design the PCB layout pattern to provide low impedance supply lines. Furthermore, connect a capacitor to ground at all power supply pins. Consider the effect of temperature and aging on the capacitance value when using electrolytic capacitors.

## 3. Ground Voltage

Ensure that no pins are at a voltage below that of the ground pin at any time, even during transient condition.

## 4. Ground Wiring Pattern

When using both small-signal and large-current ground traces, the two ground traces should be routed separately but connected to a single ground at the reference point of the application board to avoid fluctuations in the small-signal ground caused by large currents. Also ensure that the ground traces of external components do not cause variations on the ground voltage. The ground lines must be as short and thick as possible to reduce line impedance.

## 5. Recommended Operating Conditions

The function and operation of the IC are guaranteed within the range specified by the recommended operating conditions. The characteristic values are guaranteed only under the conditions of each item specified by the electrical characteristics.

## 6. Inrush Current

When power is first supplied to the IC, it is possible that the internal logic may be unstable and inrush current may flow instantaneously due to the internal powering sequence and delays, especially if the IC has more than one power supply. Therefore, give special consideration to power coupling capacitance, power wiring, width of ground wiring, and routing of connections.

## 7. Testing on Application Boards

When testing the IC on an application board, connecting a capacitor directly to a low-impedance output pin may subject the IC to stress. Always discharge capacitors completely after each process or step. The IC's power supply should always be turned off completely before connecting or removing it from the test setup during the inspection process. To prevent damage from static discharge, ground the IC during assembly and use similar precautions during transport and storage.

## 8. Inter-pin Short and Mounting Errors

Ensure that the direction and position are correct when mounting the IC on the PCB. Incorrect mounting may result in damaging the IC. Avoid nearby pins being shorted to each other especially to ground, power supply and output pin. Inter-pin shorts could be due to many reasons such as metal particles, water droplets (in very humid environment) and unintentional solder bridge deposited in between pins during assembly to name a few.

## 9. Unused Input Pins

Input pins of an IC are often connected to the gate of a MOS transistor. The gate has extremely high impedance and extremely low capacitance. If left unconnected, the electric field from the outside can easily charge it. The small charge acquired in this way is enough to produce a significant effect on the conduction through the transistor and cause unexpected operation of the IC. So unless otherwise specified, unused input pins should be connected to the power supply or ground line.

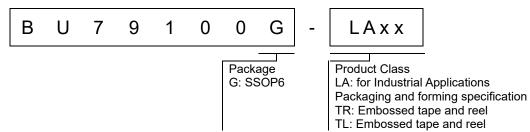
## 10. Regarding the Input Pin of the IC

In the construction of this IC, P-N junctions are inevitably formed creating parasitic diodes or transistors. The operation of these parasitic elements can result in mutual interference among circuits, operational faults, or physical damage. Therefore, conditions which cause these parasitic elements to operate, such as applying a voltage to an input pin lower than the ground voltage should be avoided. Furthermore, do not apply a voltage to the input pins when no power supply voltage is applied to the IC. Even if the power supply voltage is applied, make sure that the input pins have voltages within the values specified in the electrical characteristics of this IC.

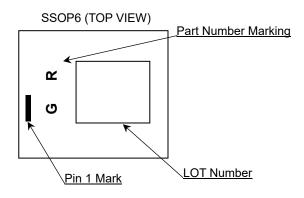
## 11. Ceramic Capacitor

When using a ceramic capacitor, determine a capacitance value considering the change of capacitance with temperature and the decrease in nominal capacitance due to DC bias and others.

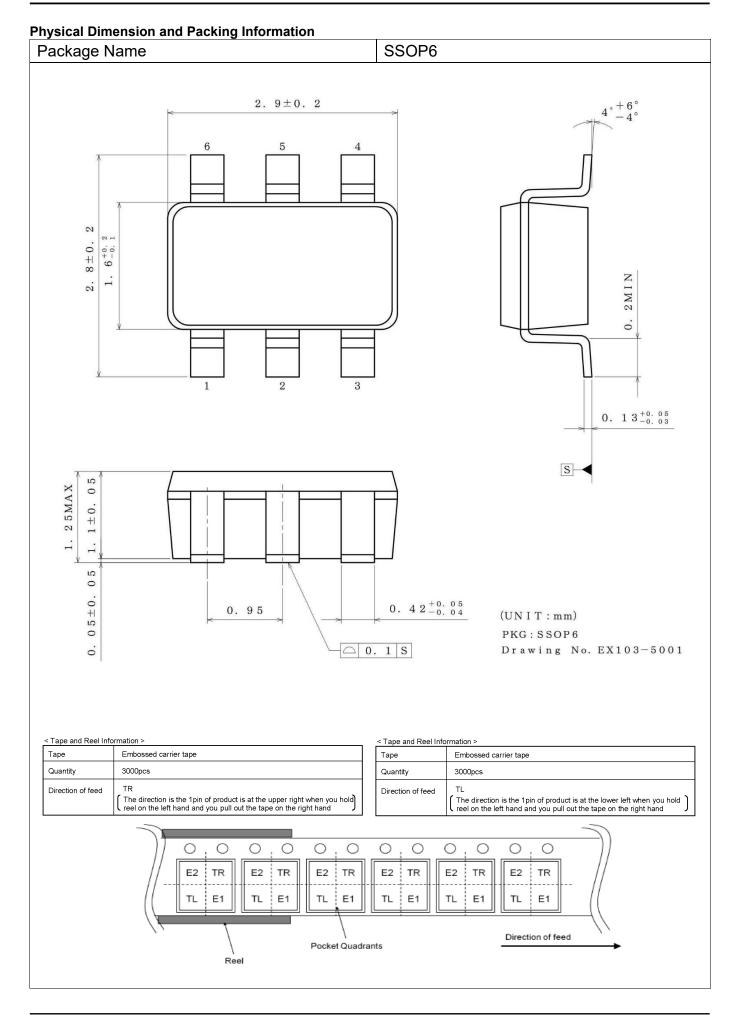
## **Ordering Information**



## **Marking Diagram**



## Datasheet



## Revision History

Date	Revision	Changes
05.Feb.2021	001	New Release
03.Jul.2024	002	Add Direction of feed

## Notice

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CLASSII	CLASSⅢ	CLASS II b		
CLASSⅣ	CLASSI	CLASSII	CLASSII	

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  - [f] Sealing or coating our Products with resin or other coating materials
  - [g] Use of our Products without cleaning residue of flux (Exclude cases where no-clean type fluxes is used. However, recommend sufficiently about the residue.); or Washing our Products by using water or water-soluble cleaning agents for cleaning residue after soldering
  - [h] Use of the Products in places subject to dew condensation
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- 6. In particular, if a transient load (a large amount of load applied in a short period of time, such as pulse, is applied, confirmation of performance characteristics after on-board mounting is strongly recommended. Avoid applying power exceeding normal rated power; exceeding the power rating under steady-state loading condition may negatively affect product performance and reliability.
- 7. De-rate Power Dissipation depending on ambient temperature. When used in sealed area, confirm that it is the use in the range that does not exceed the maximum junction temperature.
- 8. Confirm that operation temperature is within the specified range described in the product specification.
- 9. ROHM shall not be in any way responsible or liable for failure induced under deviant condition from what is defined in this document.

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- 1. When a highly active halogenous (chlorine, bromine, etc.) flux is used, the residue of flux may negatively affect product performance and reliability.
- 2. In principle, the reflow soldering method must be used on a surface-mount products, the flow soldering method must be used on a through hole mount products. If the flow soldering method is preferred on a surface-mount products, please consult with the ROHM representative in advance.

For details, please refer to ROHM Mounting specification

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- 1. If change is made to the constant of an external circuit, please allow a sufficient margin considering variations of the characteristics of the Products and external components, including transient characteristics, as well as static characteristics.
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This Product is electrostatic sensitive product, which may be damaged due to electrostatic discharge. Please take proper caution in your manufacturing process and storage so that voltage exceeding the Products maximum rating will not be applied to Products. Please take special care under dry condition (e.g. Grounding of human body / equipment / solder iron, isolation from charged objects, setting of lonizer, friction prevention and temperature / humidity control).

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  - [b] the temperature or humidity exceeds those recommended by ROHM
  - [c] the Products are exposed to direct sunshine or condensation
  - [d] the Products are exposed to high Electrostatic
- 2. Even under ROHM recommended storage condition, solderability of products out of recommended storage time period may be degraded. It is strongly recommended to confirm solderability before using Products of which storage time is exceeding the recommended storage time period.
- 3. Store / transport cartons in the correct direction, which is indicated on a carton with a symbol. Otherwise bent leads may occur due to excessive stress applied when dropping of a carton.
- 4. Use Products within the specified time after opening a humidity barrier bag. Baking is required before using Products of which storage time is exceeding the recommended storage time period.

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